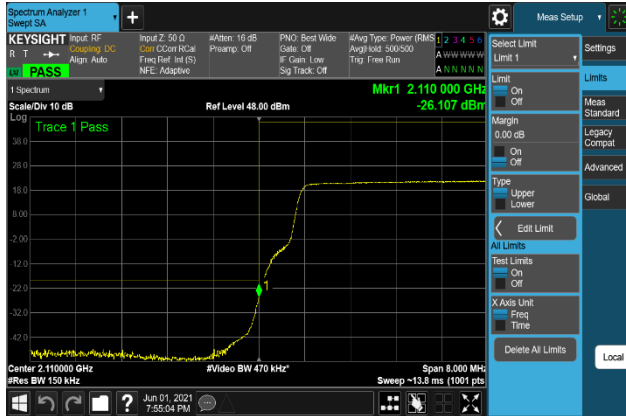
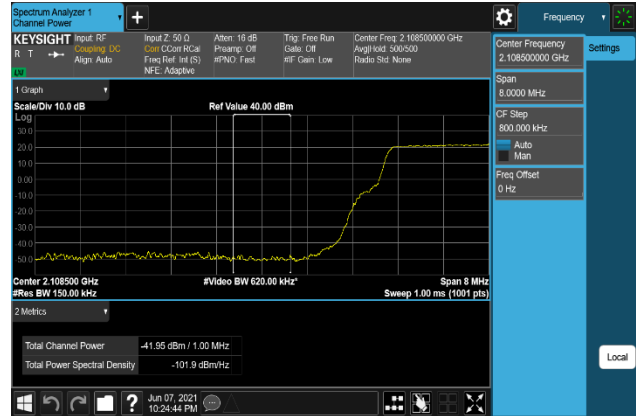




Plot 7-547. Band Edge Emission Plot
(B66_15M+10M+10M 256QAM - Low Channel, Port 3)



Plot 7-548. Band Edge Emission(Channel Power) Plot
(B66_15M+10M+10M 256QAM - Low Channel, Port 3)



Plot 7-549. Band Edge Emission Plot
(B66_15M+10M+10M QPSK - High Channel, Port 0)



Plot 7-550. Band Edge Emission(Channel Power) Plot
(B66_15M+10M+10M QPSK - High Channel, Port 0)



Plot 7-551. Band Edge Emission Plot
(B66_15M+10M+10M_16QAM - High Channel, Port 0)

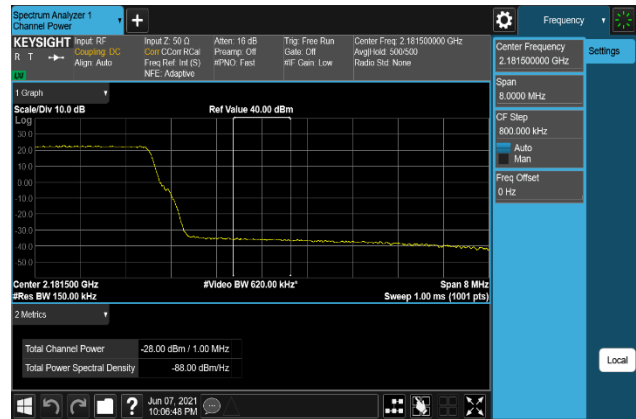


Plot 7-552. Band Edge Emission(Channel Power) Plot
(B66_15M+10M+10M_16QAM - High Channel, Port 0)

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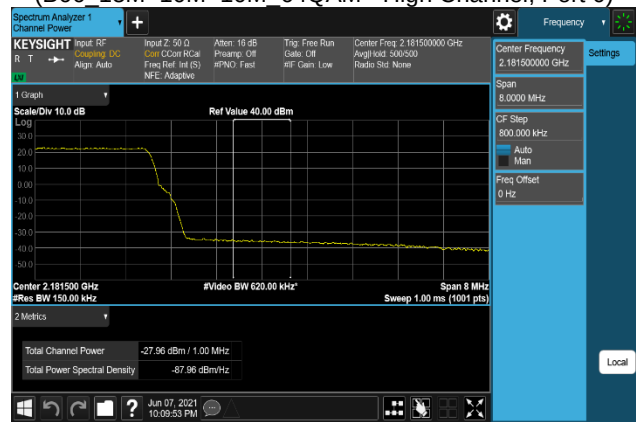
Plot 7-553. Band Edge Emission Plot
(B66_15M+10M+10M_64QAM - High Channel, Port 0)



Plot 7-554. Band Edge Emission(Channel Power) Plot
(B66_15M+10M+10M_64QAM - High Channel, Port 0)



Plot 7-555. Band Edge Emission Plot
(B66_15M+10M+10M_256QAM - High Channel, Port 0)



Plot 7-556. Band Edge Emission(Channel Power) Plot
(B66_15M+10M+10M_256QAM - High Channel, Port 0)



Plot 7-557. Band Edge Emission Plot
(B66_15M+10M+10M_QPSK - High Channel, Port 1)



Plot 7-558. Band Edge Emission(Channel Power) Plot
(B66_15M+10M+10M_QPSK - High Channel, Port 1)

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Plot 7-559. Band Edge Emission Plot
(B66_15M+10M+10M_16QAM - High Channel, Port 1)



Plot 7-560. Band Edge Emission(Channel Power) Plot
(B66_15M+10M+10M_16QAM - High Channel, Port 1)



Plot 7-561. Band Edge Emission Plot
(B66_15M+10M+10M_64QAM - High Channel, Port 1)



Plot 7-562. Band Edge Emission(Channel Power) Plot
(B66_15M+10M+10M_64QAM - High Channel, Port 1)



Plot 7-563. Band Edge Emission Plot
(B66_15M+10M+10M_256QAM - High Channel, Port 1)



Plot 7-564. Band Edge Emission(Channel Power) Plot
(B66_15M+10M+10M_256QAM - High Channel, Port 1)

FCC ID: A3LRF4402D-D1A	PCTEST ENGINEERING LABORATORY, INC.	MEASUREMENT REPORT (Class II Permissive Change)	SAMSUNG	Approved by: Technical Manager
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Plot 7-565. Band Edge Emission Plot
(B66_15M+10M+10M_QPSK - High Channel, Port 2)



Plot 7-566. Band Edge Emission(Channel Power) Plot
(B66_15M+10M+10M_QPSK - High Channel, Port 2)



Plot 7-567. Band Edge Emission Plot
(B66_15M+10M+10M_16QAM - High Channel, Port 2)



Plot 7-568. Band Edge Emission(Channel Power) Plot
(B66_15M+10M+10M_16QAM - High Channel, Port 2)



Plot 7-569. Band Edge Emission Plot
(B66_15M+10M+10M_64QAM - High Channel, Port 2)



Plot 7-570. Band Edge Emission(Channel Power) Plot
(B66_15M+10M+10M_64QAM - High Channel, Port 2)

FCC ID: A3LRF4402D-D1A	PCTEST ENGINEERING LABORATORY, INC.	MEASUREMENT REPORT (Class II Permissive Change)	SAMSUNG	Approved by: Technical Manager
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Plot 7-571. Band Edge Emission Plot
(B66_15M+10M+10M_256QAM - High Channel, Port 2)



Plot 7-572. Band Edge Emission(Channel Power) Plot
(B66_15M+10M+10M_256QAM - High Channel, Port 2)



Plot 7-573. Band Edge Emission Plot
(B66_15M+10M+10M_QPSK - High Channel, Port 3)



Plot 7-574. Band Edge Emission(Channel Power) Plot
(B66_15M+10M+10M_QPSK - High Channel, Port 3)



Plot 7-575. Band Edge Emission Plot
(B66_15M+10M+10M_16QAM - High Channel, Port 3)



Plot 7-576. Band Edge Emission(Channel Power) Plot
(B66_15M+10M+10M_16QAM - High Channel, Port 3)

FCC ID: A3LRF4402D-D1A	PCTEST ENGINEERING LABORATORY, INC.	MEASUREMENT REPORT (Class II Permissive Change)	SAMSUNG	Approved by: Technical Manager
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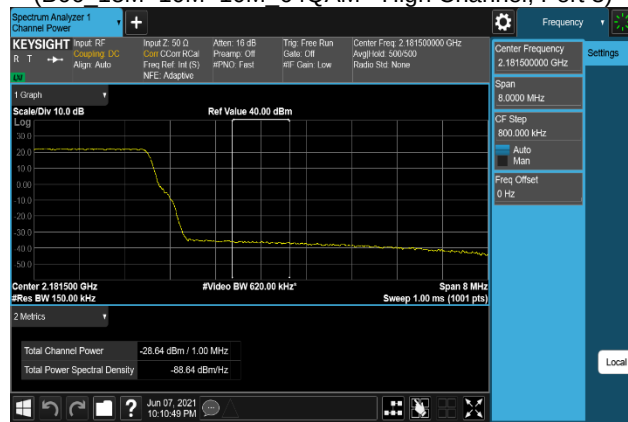
Plot 7-577. Band Edge Emission Plot
(B66_15M+10M+10M_64QAM - High Channel, Port 3)



Plot 7-579. Band Edge Emission Plot
(B66_15M+10M+10M_256QAM - High Channel, Port 3)



Plot 7-578. Band Edge Emission(Channel Power) Plot
(B66_15M+10M+10M_64QAM - High Channel, Port 3)



Plot 7-580. Band Edge Emission(Channel Power) Plot
(B66_15M+10M+10M_256QAM - High Channel, Port 3)

FCC ID: A3LRF4402D-D1A	PCTEST ENGINEERING LABORATORY, INC.	MEASUREMENT REPORT (Class II Permissive Change)	SAMSUNG	Approved by: Technical Manager
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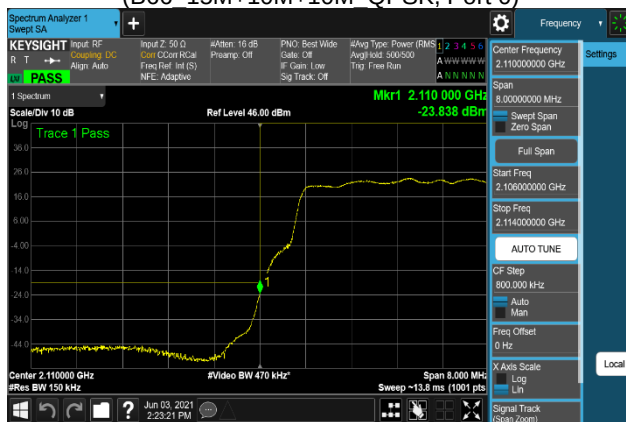
- B66 15M+10M+10M Non-Contiguous



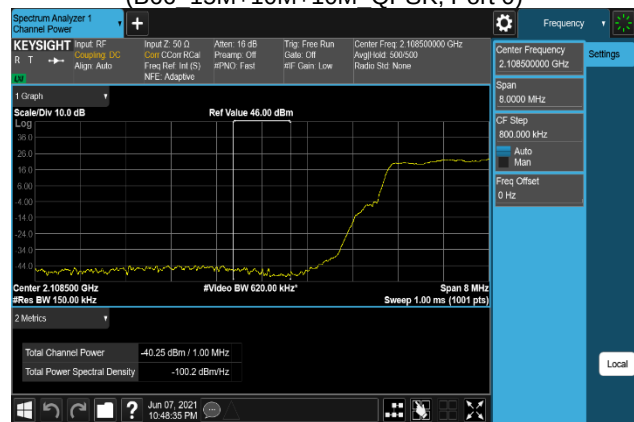
Plot 7-581. Band Edge Emission Plot
(B66 15M+10M+10M QPSK, Port 0)



Plot 7-582. Band Edge Emission(Channel Power) Plot
(B66 15M+10M+10M QPSK, Port 0)



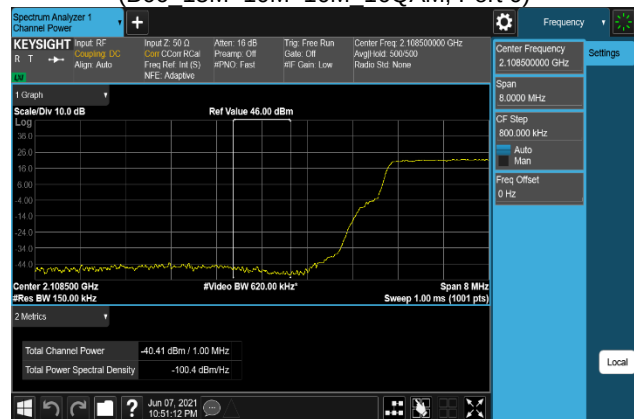
Plot 7-583. Band Edge Emission Plot
(B66 15M+10M+10M 16QAM, Port 0)



Plot 7-584. Band Edge Emission(Channel Power) Plot
(B66 15M+10M+10M 16QAM, Port 0)



Plot 7-585. Band Edge Emission Plot
(B66 15M+10M+10M 64QAM, Port 0)

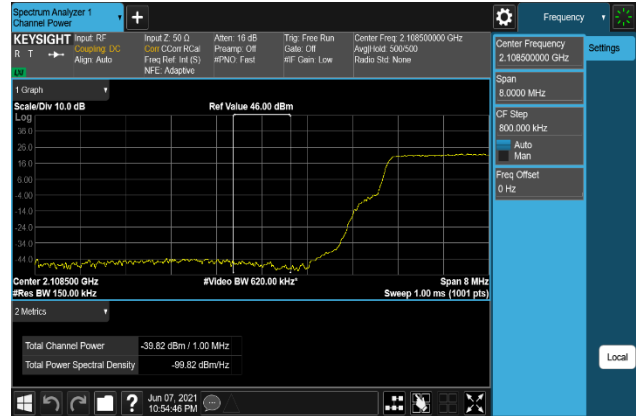


Plot 7-586. Band Edge Emission(Channel Power) Plot
(B66 15M+10M+10M 64QAM, Port 0)

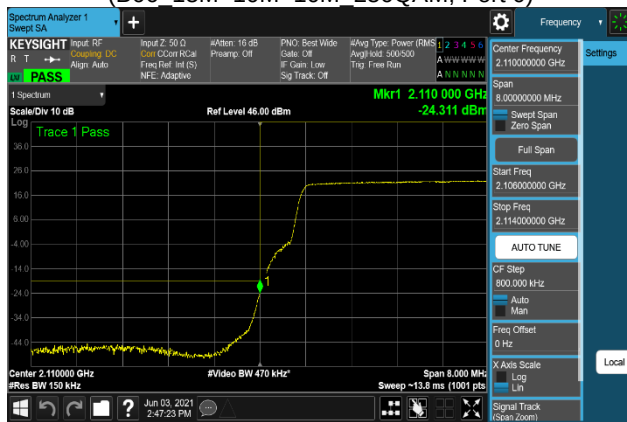
FCC ID: A3LRF4402D-D1A	PCTEST ENGINEERING LABORATORY, INC.	MEASUREMENT REPORT (Class II Permissive Change)	SAMSUNG	Approved by: Technical Manager
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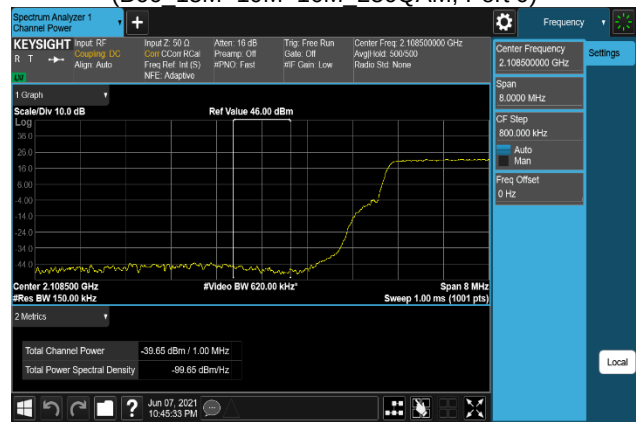
Plot 7-587. Band Edge Emission Plot
(B66_15M+10M+10M_256QAM, Port 0)



Plot 7-588. Band Edge Emission(Channel Power) Plot
(B66_15M+10M+10M_256QAM, Port 0)



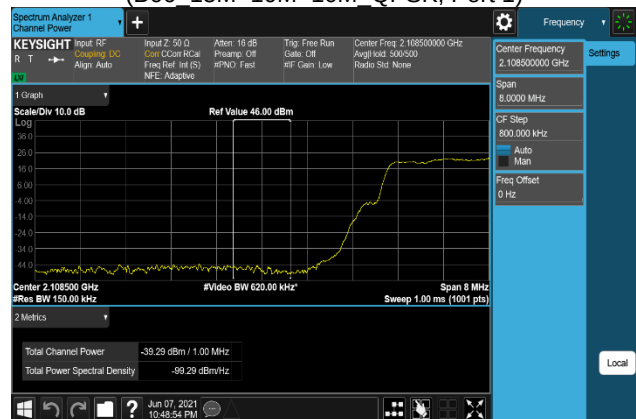
Plot 7-589. Band Edge Emission Plot
(B66_15M+10M+10M_QPSK, Port 1)



Plot 7-590. Band Edge Emission(Channel Power) Plot
(B66_15M+10M+10M_QPSK, Port 1)

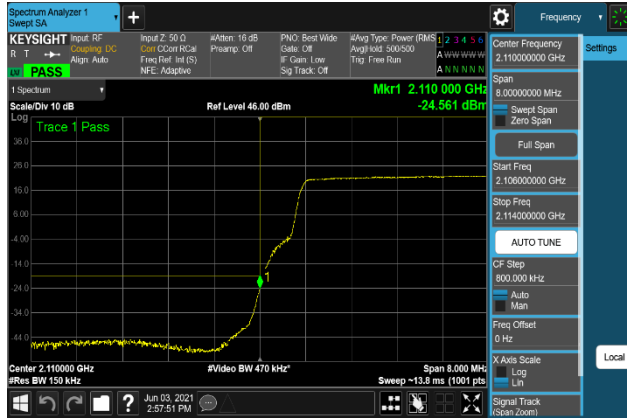


Plot 7-591. Band Edge Emission Plot
(B66_15M+10M+10M_16QAM, Port 1)



Plot 7-592. Band Edge Emission(Channel Power) Plot
(B66_15M+10M+10M_16QAM, Port 1)

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Plot 7-593. Band Edge Emission Plot
(B66_15M+10M+10M_64QAM, Port 1)



Plot 7-594. Band Edge Emission(Channel Power) Plot
(B66_15M+10M+10M_64QAM, Port 1)



Plot 7-595. Band Edge Emission Plot
(B66_15M+10M+10M_256QAM, Port 1)



Plot 7-596. Band Edge Emission(Channel Power) Plot
(B66_15M+10M+10M_256QAM, Port 1)



Plot 7-597. Band Edge Emission Plot
(B66_15M+10M+10M_QPSK, Port 2)



Plot 7-598. Band Edge Emission(Channel Power) Plot
(B66_15M+10M+10M_QPSK, Port 2)

FCC ID: A3LRF4402D-D1A	PCTEST ENGINEERING LABORATORY, INC.	MEASUREMENT REPORT (Class II Permissive Change)	SAMSUNG	Approved by: Technical Manager
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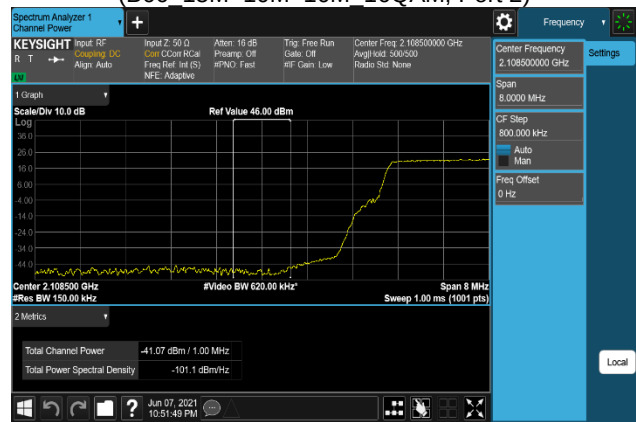
Plot 7-599. Band Edge Emission Plot
(B66 15M+10M+10M 16QAM, Port 2)



Plot 7-600. Band Edge Emission(Channel Power) Plot
(B66 15M+10M+10M 16QAM, Port 2)



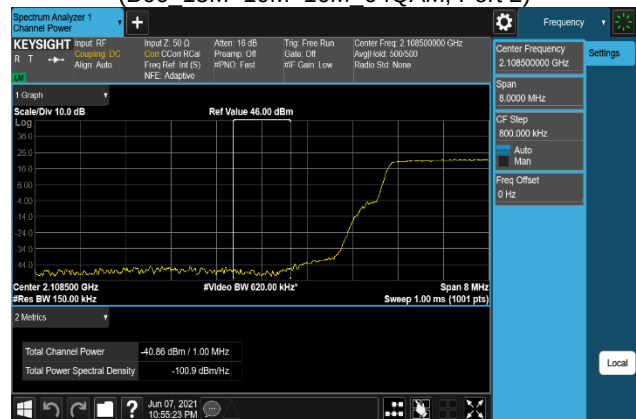
Plot 7-601. Band Edge Emission Plot
(B66 15M+10M+10M 64QAM, Port 2)



Plot 7-602. Band Edge Emission(Channel Power) Plot
(B66 15M+10M+10M 64QAM, Port 2)

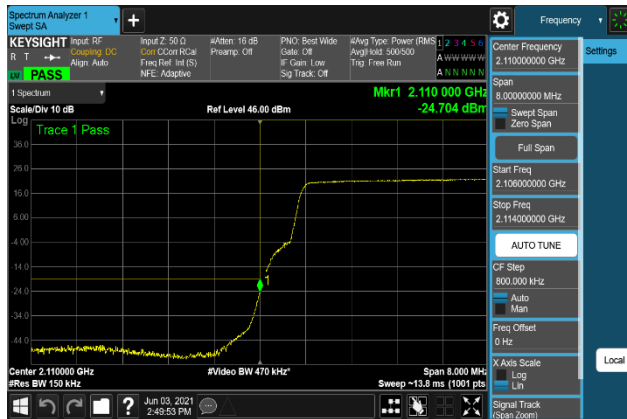


Plot 7-603. Band Edge Emission Plot
(B66_15M+10M+10M_256QAM, Port 2)

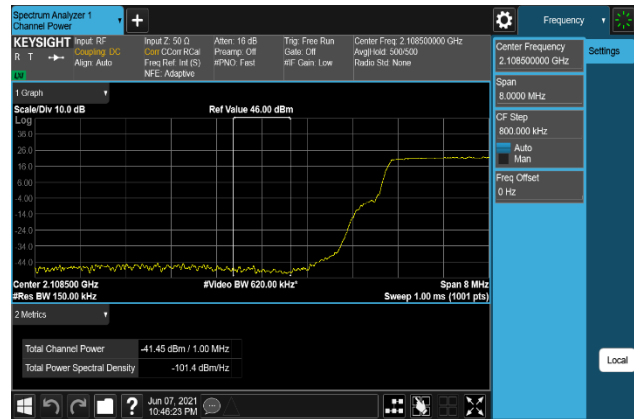


Plot 7-604. Band Edge Emission(Channel Power) Plot
(B66_15M+10M+10M_256QAM, Port 2)

FCC ID: A3LRF4402D-D1A	PCTEST ENGINEERING LABORATORY, INC.	MEASUREMENT REPORT (Class II Permissive Change)	SAMSUNG	Approved by: Technical Manager
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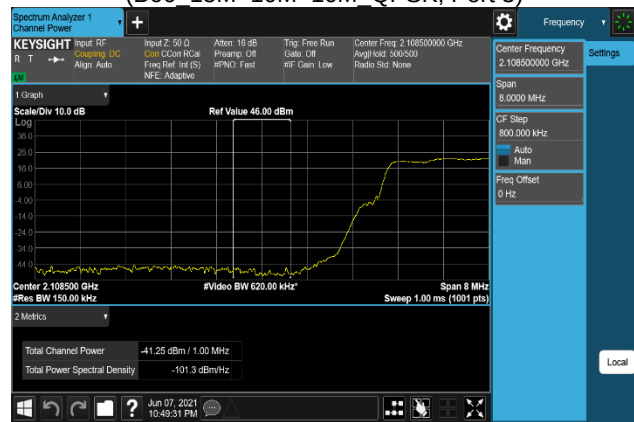
Plot 7-605. Band Edge Emission Plot
(B66_15M+10M+10M_QPSK, Port 3)



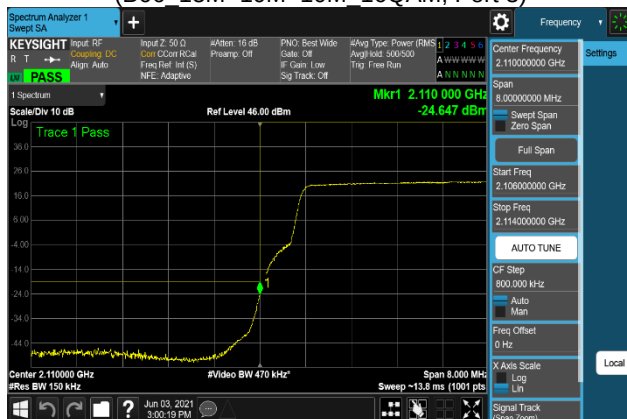
Plot 7-606. Band Edge Emission(Channel Power) Plot
(B66_15M+10M+10M_QPSK, Port 3)



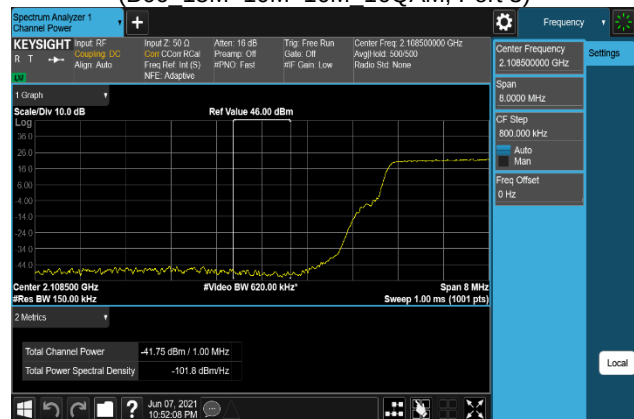
Plot 7-607. Band Edge Emission Plot
(B66_15M+10M+10M_16QAM, Port 3)



Plot 7-608. Band Edge Emission(Channel Power) Plot
(B66_15M+10M+10M_16QAM, Port 3)

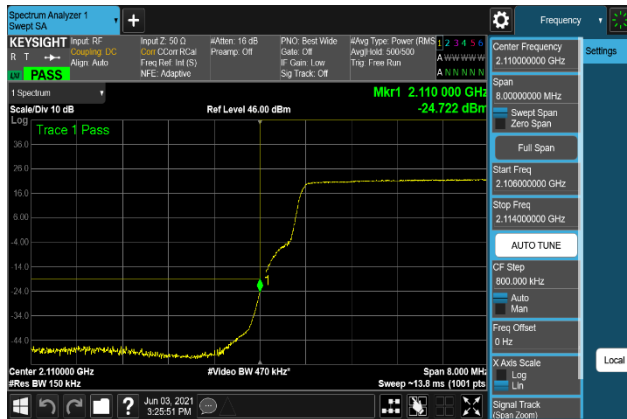


Plot 7-609. Band Edge Emission Plot
(B66_15M+10M+10M_64QAM, Port 3)

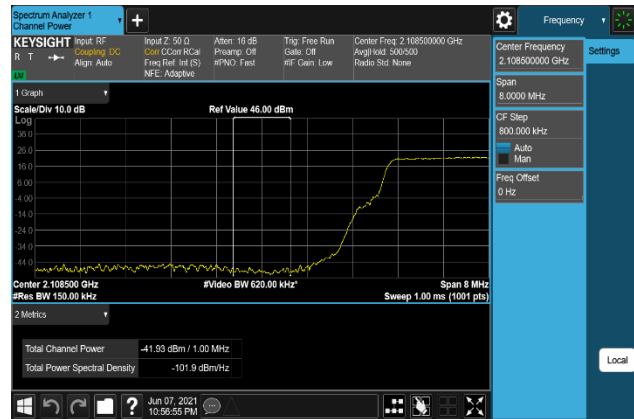


Plot 7-610. Band Edge Emission(Channel Power) Plot
(B66_15M+10M+10M_64QAM, Port 3)

FCC ID: A3LRF4402D-D1A	PCTEST ENGINEERING LABORATORY, INC.	MEASUREMENT REPORT (Class II Permissive Change)	SAMSUNG	Approved by: Technical Manager
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Plot 7-611. Band Edge Emission Plot
(B66_15M+10M+10M_256QAM, Port 3)



Plot 7-612. Band Edge Emission(Channel Power) Plot
(B66_15M+10M+10M_256QAM, Port 3)



Plot 7-613. Band Edge Emission Plot
(B66_15M+10M+10M_QPSK, Port 0)



Plot 7-614. Band Edge Emission(Channel Power) Plot
(B66_15M+10M+10M_QPSK, Port 0)



Plot 7-615. Band Edge Emission Plot
(B66_15M+10M+10M_16QAM, Port 0)



Plot 7-616. Band Edge Emission(Channel Power) Plot
(B66_15M+10M+10M_16QAM, Port 0)

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Plot 7-617. Band Edge Emission Plot
(B66_15M+10M+10M_64QAM, Port 0)



Plot 7-618. Band Edge Emission(Channel Power) Plot
(B66_15M+10M+10M_64QAM, Port 0)



Plot 7-619. Band Edge Emission Plot
(B66_15M+10M+10M_256QAM, Port 0)



Plot 7-620. Band Edge Emission(Channel Power) Plot
(B66_15M+10M+10M_256QAM, Port 0)



Plot 7-621. Band Edge Emission Plot
(B66_15M+10M+10M_QPSK, Port 1)



Plot 7-622. Band Edge Emission(Channel Power) Plot
(B66_15M+10M+10M_QPSK, Port 1)

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Plot 7-623. Band Edge Emission Plot
(B66 15M+10M+10M 16QAM, Port 1)



Plot 7-624. Band Edge Emission(Channel Power) Plot
(B66 15M+10M+10M 16QAM, Port 1)



Plot 7-625. Band Edge Emission Plot
(B66 15M+10M+10M 64QAM, Port 1)



Plot 7-626. Band Edge Emission(Channel Power) Plot
(B66 15M+10M+10M 64QAM, Port 1)



Plot 7-627. Band Edge Emission Plot
(B66_15M+10M+10M_256QAM, Port 1)



Plot 7-628. Band Edge Emission(Channel Power) Plot
(B66_15M+10M+10M_256QAM, Port 1)

FCC ID: A3LRF4402D-D1A	PCTEST ENGINEERING LABORATORY, INC.	MEASUREMENT REPORT (Class II Permissive Change)	SAMSUNG	Approved by: Technical Manager
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